An external diagnosis method for network-on-a-chip

Raik, Jaan; Govind, Vineeth; **Ubar, Raimund-Johannes** IEEE/ACM Design Automation and Test in Europe, Workshop on Diagnostic Services in Networks-on-Chips - Test, Debug and On-line Monitoring : April 16-20, 2007, Nice, France 2007 / [2] p. : ill